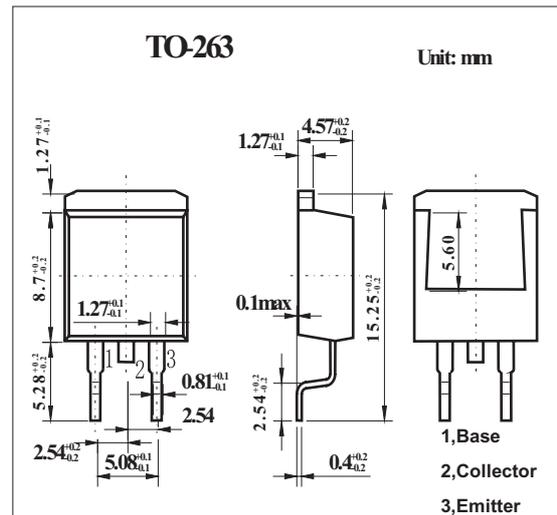


NPN Triple Diffused Planar Silicon Transistor

2SC4601

■ Features

- Surface mount type device making the following possible.
- Reduction in the number of manufacturing processes for 2SC4601-applied equipment.
- High density surface mount applications.
- Small size of 2SC4601-applied equipment.
- High breakdown voltage, high reliability.
- Fast switching speed.
- Wide ASO.
- Adoption of MBIT process.

■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Collector-base voltage	V_{CBO}	1100	V
Collector-emitter voltage	V_{CEO}	800	V
Emitter-base voltage	V_{EBO}	7	V
Collector current (DC)	I_C	1.5	A
Collector current (Pulse) *	I_{CP}	5	
Base current	I_B	0.8	A
Collector power dissipation	P_C	$T_a = 25^\circ\text{C}$	W
		$T_c = 25^\circ\text{C}$	
Junction temperature	T_j	150	$^\circ\text{C}$
Storage temperature range	T_{stg}	-55 to +150	$^\circ\text{C}$

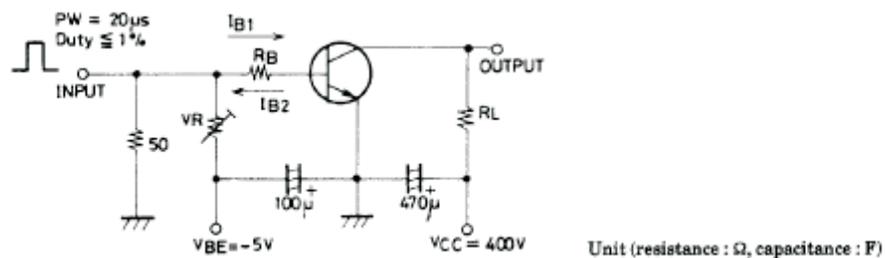
* $PW \leq 300\text{ms}$, duty cycle $\leq 10\%$

2SC4601

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit
Collector cut-off current	I _{CBO}	V _{CB} = 800 V, I _E = 0			10	μA
Emitter cut-off current	I _{EBO}	V _{EB} = 5 V, I _C = 0			10	μA
DC current gain	h _{FE}	V _{CE} = 5 V, I _C = 0.1A	10		40	
		V _{CE} = 5 V, I _C = 0.5A	8			
Gain-Bandwidth product	f _T	V _{CE} = 10 V, I _C = 0.1A		15		MHz
Output Capacitance	C _{ob}	V _{CB} = 10V, f = 1MHz		35		pF
Collector-emitter saturation voltage	V _{CE(sat)}	I _C = 0.75 A, I _B = 0.15 A			2.0	V
Base-emitter saturation voltage	V _{BE(sat)}	I _C = 0.75 A, I _B = 0.15 A			1.5	V
Collector-base breakdown voltage	V _{(BR)CBO}	I _C = 1 mA, I _E = 0	1100			V
Collector-emitter breakdown voltage	V _{(BR)CEO}	I _C = 5 mA, R _{BE} = ∞	800			V
Emitter-to-Base Breakdown Voltage	V _{(BR)EBO}	I _E = 1mA, I _C = 0	7			V
Collector-to-Emitter Sustain Voltage	V _{CEO(SUS)}	I _C = 0.75A, I _{B1} = -I _{B2} = 0.15A, L = 50mH	800			V
Turn-ON time	t _{on}	I _C = 1A, I _{B1} = 0.2A, I _{B2} = -0.4A, R _L = 400 Ω, V _{CC} = 400V			0.5	μs
Storage time	t _{stg}				3.0	
Fall time	t _f				0.3	

■ Switching Time Test Circuit

■ h_{FE} Classification

Rank	K	L	M
h _{FE}	10 to 20	15 to 30	20 to 40